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| FORM PTO 449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT | ATTY. DOCKET NO. CiphBio-11 CON | SERIAL NO. 10/758,326 |
| | APPLICANT Sidney E. Buttrill, Jr. | |
| | FILING DATE January 14, 2004 | GROUP 2878 2881 |

U.S. PATENT DOCUMENTS

| EXAMINER INITIALS | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
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Andrieta Keller

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| FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT | ATTY. DOCKET NO. CiphBio-11 CON | SERIAL NO. 10/758,326 |
| | APPLICANT Sidney E. Buttrill, Jr. | |
| | FILING DATE January 14, 2004 | GROUP 2878 2881 |

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| EXAMINER INITIALS | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION | |
|----------------------|--------------------|---------|---------|-------|----------|-------------|----|
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